

**CLAIMS**

1. A semiconductor tester comprising:  
a driver circuit for supplying a signal of a predetermined waveform to be applied to an IC pin of a device under test (DUT) via a predetermined transmission line, wherein said driver circuit comprises:  
means for receiving a driver input pulse of a logic signal, detecting a rising edge of said driver input pulse and generating a differential rise correction pulse to perform a peaking correction on a rise of a waveform;  
means for receiving a driver input pulse of a logic signal, detecting a falling edge of said driver input pulse and generating a differential fall correction pulse to perform a peaking correction on a fall of a waveform; and  
means for performing said peaking correction on a rising part of a waveform outputted from said driver circuit based on said differential rise correction pulse, whereas performing a peaking correction on a falling part of a waveform outputted from said driver circuit based on said differential fall correction pulse.
2. A semiconductor tester comprising:  
a driver circuit for supplying a signal of a predetermined waveform to be applied to an IC pin of a device under test (DUT) via a predetermined transmission line,  
wherein said driver circuit comprises:  
drive pulse generating means for receiving a rising edge of a driver input pulse of a logic signal and generating a differential rise correction pulse, whereas receiving a falling edge of a driver input pulse of a logic signal and generating

a differential fall correction pulse;

a rise pulse superimposing section for receiving said differential rise correction pulse and generating a first sink current whose current amount corresponds to said differential rise correction pulse;

a fall pulse superimposing section for receiving said fall correction pulse and generating a second sink current whose current amount corresponds to said fall correction pulse; and

preceding and last stages of said driver circuit for outputting a test waveform to be supplied to said DUT by receiving said first sink current and performing a peaking correction on a rising side of said test waveform, while receiving said second sink current and performing a peaking correction on a falling side of said test waveform.

3. A semiconductor tester comprising:

a driver circuit for supplying a signal of a predetermined waveform to be applied to an IC pin of a device under test (DUT) via a predetermined transmission line,

wherein said driver circuit comprises:

a plurality (n) of drive pulse generating means, each of which receives a rising edge of a driver input pulse of a logic signal and generates a differential rise correction pulse so that said rise correction pulse has a different pulse period, whereas receiving a falling edge of a driver input pulse of a logic signal and generating a differential fall correction pulse so that said fall correction pulse has a different pulse period;

a plurality (n) of rise pulse superimposing sections, each of which receives a plurality (n) of said differential rise correction pulses and generates a first sink current of a predetermined sink current amount for a predetermined pulse

period;

a plurality (n) of fall pulse superimposing sections, each of which receives a plurality (n) of said fall correction pulses and generates a second sink current of a predetermined sink current amount for a predetermined pulse period; and

preceding and last stages of said driver circuit for outputting a test waveform to be supplied to said DUT by receiving a plurality (n) of said first sink currents and performing a peaking correction on a rising side of said test waveform, while receiving a plurality (n) of said second sink currents and performing a peaking correction on a falling side of said test waveform.

4. A semiconductor tester as claimed in claim 2 or 3, wherein said drive pulse generating means receives a drive input pulse of a logic signal,

firstly detects a rising edge of said driver input pulse and generates a differential rise correction pulse of a predetermined period,

secondly detects a falling edge of said driver input pulse and generates a differential fall correction pulse of a predetermined period, and

thirdly generates a differential driver pulse corresponding to said driver input pulse.

5. A semiconductor tester as claimed in claim 2 or 3, wherein said rise pulse superimposing section comprises a first constant current source and first and second transistors of a first differential amplification configuration,

said first constant current source is coupled to emitters of said both transistors and makes a constant current amount

flowing through any of said both transistors be constant, and  
said first and second transistors receive said differential  
rise correction pulse in base terminals thereof and generate  
a first sink current of a constant current amount on which current  
switching has been performed.

6. A semiconductor tester as claimed in claim 2 or 3,  
wherein said fall pulse superimposing section comprises  
a second constant current source and third and fourth transistors  
of a second differential amplification configuration,  
said second constant current source is coupled to emitters  
of said both transistors and makes a constant current amount  
flowing through any of said both transistors be constant, and  
said third and fourth transistors receive said differential  
fall correction pulse in base terminals thereof and generate  
a second sink current of a constant current amount on which current  
switching has been performed.

7. A semiconductor tester as claimed in claim 2 or 3,  
wherein said preceding stage of said driver circuit, which  
supplies a differential drive voltage signal to determine a voltage  
level, which is a high or low level, to be outputted from said  
last stage, comprises first and second resistors, a third constant  
current source, and fifth and sixth transistors of a third  
differential amplification configuration,

said first resistor, which is a load resistor coupled  
to a collector of said fifth transistor, is coupled to a collector  
terminal of said first transistor for generating said first sink  
current of said rise pulse superimposing section,

said second resistor, which is a load resistor coupled  
to a collector of said sixth transistor, is coupled to a collector

terminal of said third transistor for generating said second sink current of said fall pulse superimposing section,

said third constant current source is coupled to both emitters of said third differential transistors and allows a predetermined constant current amount to flow, and

current switching is performed based on a differential drive pulse received by said both transistors of said third differential amplification configuration, while said differential drive voltage signal weighted by said first and second sink currents is outputted from collectors of said both transistors and supplied to said last stage.

8. A semiconductor tester as claimed in claim 2 or 3, wherein said last stage of said driver circuit comprises seventh and eighth transistors of a fourth differential amplification configuration, first and second current dividing resistors, a first load resistor, and a fourth constant current source,

said seventh and eighth transistors receive said differential drive voltage signal outputted from said preceding stage of said driver circuit in a base input terminal thereof, amplify said differential drive voltage signal in a predetermined manner, and generate an applied signal of a predetermined waveform to be supplied to said DUT from a collector terminal of said eighth transistor,

said first and second current dividing resistors, which are emitter resistors individually coupled to emitters of said both transistors, while other ends of said current dividing resistors are coupled to said fourth constant current source,

said first load resistor, which becomes a load resistor coupled to said constant current source and said collector terminal

of said eighth transistor, supplies said applied signal of a predetermined waveform to said DUT, and

    said fourth constant current source becomes a constant current source inserted between a negative power source and said first and second current dividing resistors.

9.     A semiconductor tester as claimed in claim 5 or 6,  
        wherein said first or second constant current source is a fixed constant current source for supplying an invariable constant current amount or a variable constant current source whose constant current amount is externally changeable.